TPD1E0B04 1-Channel ESD Protection Diode for USB Type-C and Antenna Protection

1 Features
• IEC 61000-4-2 Level 4 (Contact) ESD Protection
  – ±8-kV Contact Discharge
  – ±9-kV Air Gap Discharge
• IEC 61000-4-4 EFT Protection
  – 80 A (5/50 ns)
• IEC 61000-4-5 Surge Protection
  – 1.7 A (8/20 µs)
• IO Capacitance: 0.13 to 0.15 pF (Typical), 0.15 to 0.18 pF (Maximum)
• DC Breakdown Voltage: 6.7 V (Typical)
• Ultra Low Leakage Current: 10 nA (Maximum)
• Low ESD Clamping Voltage
• Supports High Speed Interfaces up to 20 Gbps
• Low Insertion Loss: >30 GHz (–3 dB Bandwidth)
• Industrial Temperature Range: –40°C to +125°C
• Ultra-small 0201 and 0402 footprints

2 Applications
• End Equipment
  – Laptops and Desktops
  – Mobile and Tablets
  – Set-Top Boxes
  – TV and Monitors
  – USB Dongles
  – Docking Stations
• Interfaces
  – USB Type-C
  – Thunderbolt 3
  – USB 3.1 Gen 2
  – HDMI 2.0/1.4
  – USB 3.0
  – DisplayPort 1.3
  – PCI Express 3.0
  – Antenna

3 Description
The TPD1E0B04 is a bidirectional TVS ESD protection diode array for USB Type-C and Thunderbolt 3 circuit protection. The TPD1E0B04 is rated to dissipate ESD strikes at the maximum level specified in the IEC 61000-4-2 international standard (Level 4).

This device features a 0.13-pF IO capacitance per channel (DPL package) making it ideal for protecting high-speed interfaces up to 20 Gbps such as USB 3.1 Gen 2, Thunderbolt 3, and Antenna. The low dynamic resistance and low clamping voltage ensure system level protection against transient events.

The TPD1E0B04 is offered in the industry standard 0201 (DPL) and 0402 (DPY) packages.

Device Information

<table>
<thead>
<tr>
<th>PART NUMBER</th>
<th>PACKAGE</th>
<th>BODY SIZE (NOM)</th>
</tr>
</thead>
<tbody>
<tr>
<td>TPD1E0B04</td>
<td>X2SON (2)</td>
<td>0.60 mm x 0.30 mm</td>
</tr>
<tr>
<td></td>
<td>X1SON (2)</td>
<td>1.00 mm x 0.60 mm</td>
</tr>
</tbody>
</table>

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Typical Application
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4 Revision History

Changes from Revision A (June 2016) to Revision B Page

- Added "and 0402 (DPY) packages." to the Description, and package "X1SON (2)" to the Device Information table .... 1
- Changed the DPY Package From: Preview To Production ................................................................. 3
- Added the DPY (X1SON) package to the Thermal Information table .................................................... 4
- Added DPY values to C1 Line capacitance in the Electrical Characteristics table ........................................ 5
- Added "(DPL Package)" to the title of Figure 6 .................................................................................. 6
- Added Figure 7 ................................................................................................................................. 6
- Added curves for the DPY package to Figure 10 and Figure 11 .......................................................... 6
- Added curve for the DPY package to Figure 17 ................................................................................ 13
- Added curve for the DPY package to Figure 19 ................................................................................ 15
- Added curve for the DPY package to Figure 21 ................................................................................ 15

Changes from Original (March 2016) to Revision A Page

- Changed device status from Product Preview to Production Data .......................................................... 1
5 Pin Configuration and Functions

<table>
<thead>
<tr>
<th>PIN</th>
<th>I/O</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>NO.</td>
<td>NAME</td>
<td></td>
</tr>
<tr>
<td>1</td>
<td>IO</td>
<td>ESD Protected Channel. If used as ESD IO, connect pin 2 to ground</td>
</tr>
<tr>
<td>2</td>
<td>IO</td>
<td>ESD Protected Channel. If used as ESD IO, connect pin 1 to ground</td>
</tr>
</tbody>
</table>
6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)\(^{(1)}\)

<table>
<thead>
<tr>
<th></th>
<th>MIN</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>Electrical fast transient</td>
<td>80</td>
<td></td>
<td>A</td>
</tr>
<tr>
<td>Peak pulse IEC 61000-4-5 power (t&lt;sub&gt;p&lt;/sub&gt; - 8/20 µs)</td>
<td>15</td>
<td></td>
<td>W</td>
</tr>
<tr>
<td>Peak pulse IEC 61000-4-5 current (t&lt;sub&gt;p&lt;/sub&gt; - 8/20 µs)</td>
<td>1.7</td>
<td></td>
<td>A</td>
</tr>
<tr>
<td>T&lt;sub&gt;A&lt;/sub&gt; Traffic JA temperature</td>
<td>–40</td>
<td>125</td>
<td>°C</td>
</tr>
<tr>
<td>T&lt;sub&gt;stg&lt;/sub&gt; Storage temperature</td>
<td>–65</td>
<td>155</td>
<td>°C</td>
</tr>
</tbody>
</table>

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

<table>
<thead>
<tr>
<th>V&lt;sub&gt;(ESD)&lt;/sub&gt;</th>
<th>VALUE</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>Electrostatic discharge</td>
<td>±2500</td>
<td>V</td>
</tr>
<tr>
<td>Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001(^{(1)})</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Charged-device model (CDM), per JEDEC specification JESD22-C101(^{(2)})</td>
<td>±1000</td>
<td>V</td>
</tr>
</tbody>
</table>

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 ESD Ratings—IEC Specification

<table>
<thead>
<tr>
<th>V&lt;sub&gt;(ESD)&lt;/sub&gt;</th>
<th>VALUE</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>Electrostatic discharge</td>
<td>±8000</td>
<td>V</td>
</tr>
<tr>
<td>IEC 61000-4-2 contact discharge</td>
<td></td>
<td></td>
</tr>
<tr>
<td>IEC 61000-4-2 air-gap discharge</td>
<td>±9000</td>
<td>V</td>
</tr>
</tbody>
</table>

6.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

<table>
<thead>
<tr>
<th>V&lt;sub&gt;I&lt;/sub&gt;</th>
<th>Input pin voltage</th>
<th>MIN</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>T&lt;sub&gt;A&lt;/sub&gt;</td>
<td>Operating free-air temperature</td>
<td>–40</td>
<td>125</td>
<td>°C</td>
</tr>
</tbody>
</table>

6.5 Thermal Information

<table>
<thead>
<tr>
<th>THERMAL METRIC(^{(1)})</th>
<th>TPD1E0B04</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td>DPL (X2SON)</td>
</tr>
<tr>
<td></td>
<td>2 PINS</td>
</tr>
<tr>
<td>R&lt;sub&gt;JA&lt;/sub&gt;</td>
<td>Junction-to-ambient thermal resistance</td>
</tr>
<tr>
<td>R&lt;sub&gt;JC(top)&lt;/sub&gt;</td>
<td>Junction-to-case (top) thermal resistance</td>
</tr>
<tr>
<td>R&lt;sub&gt;JB&lt;/sub&gt;</td>
<td>Junction-to-board thermal resistance</td>
</tr>
<tr>
<td>ψ&lt;sub&gt;JT&lt;/sub&gt;</td>
<td>Junction-to-top characterization parameter</td>
</tr>
<tr>
<td>ψ&lt;sub&gt;JB&lt;/sub&gt;</td>
<td>Junction-to-board characterization parameter</td>
</tr>
<tr>
<td>R&lt;sub&gt;JC(bot)&lt;/sub&gt;</td>
<td>Junction-to-case (bottom) thermal resistance</td>
</tr>
</tbody>
</table>

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.
### 6.6 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>TEST CONDITIONS</th>
<th>MIN</th>
<th>TYP</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>(V_{\text{RWM}}) Reverse stand-off voltage</td>
<td>(i_\text{O} &lt; 10\ nA)</td>
<td>(–3.6)</td>
<td>3.6</td>
<td>(V)</td>
<td></td>
</tr>
<tr>
<td>(V_{\text{BRF}}) Breakdown voltage, IO pin to GND</td>
<td>Measured as the maximum voltage before device snaps back into (V_{\text{HOLD}}) voltage</td>
<td>6.7</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(V_{\text{BRR}}) Breakdown voltage, GND to IO pin</td>
<td>Measured as the maximum voltage before device snaps back into (V_{\text{HOLD}}) voltage</td>
<td>(–6.7)</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(V_{\text{HOLD}}) Holding voltage</td>
<td>(i_\text{O} = 1\ mA, T_\text{A} = 25°C)</td>
<td>5</td>
<td>5.7</td>
<td>6.5</td>
<td>(V)</td>
</tr>
<tr>
<td>(V_{\text{CLAMP}}) Clamping voltage</td>
<td>(i_{\text{PP}} = 1\ A, \text{TLP, from IO to GND})</td>
<td>7.2</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>(i_{\text{PP}} = 5\ A, \text{TLP, from IO to GND})</td>
<td>10.1</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>(i_{\text{PP}} = 16\ A, \text{TLP, from IO to GND})</td>
<td>19</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>(i_{\text{PP}} = 1\ A, \text{TLP, from GND to IO})</td>
<td>7.2</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>(i_{\text{PP}} = 5\ A, \text{TLP, from GND to IO})</td>
<td>10.1</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>(i_{\text{PP}} = 16\ A, \text{TLP, from GND to IO})</td>
<td>19</td>
<td>(V)</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(I_{\text{LEAK}}) Leakage current, IO to GND</td>
<td>(V_\text{IO} = \pm 2.5\ V)</td>
<td>10</td>
<td>(nA)</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(R_{\text{DYN}}) Dynamic resistance</td>
<td>IO to GND</td>
<td>1</td>
<td>(\Omega)</td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>GND to IO</td>
<td>1</td>
<td>(\Omega)</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(C_\text{L}) Line capacitance</td>
<td>DPL Package</td>
<td>(V_\text{IO} = 0\ V, f = 1\ MHz, \text{IO to GND})</td>
<td>0.13</td>
<td>0.15</td>
<td>(\text{pF})</td>
</tr>
<tr>
<td></td>
<td>DPY Package</td>
<td>(T_\text{A} = 25°C)</td>
<td>0.15</td>
<td>0.18</td>
<td>(\text{pF})</td>
</tr>
</tbody>
</table>
6.7 Typical Characteristics

Figure 1. Positive TLP Curve

Figure 2. Negative TLP Curve

Figure 3. 8-kV IEC Waveform

Figure 4. –8-kV IEC Waveform

Figure 5. Surge Curve (t<sub>p</sub> = 8/20μs), IO Pin to GND

Figure 6. Capacitance vs. Bias Voltage (DPL Package)
Typical Characteristics (continued)

**Figure 7. Capacitance vs. Bias Voltage (DPY Package)**

![Capacitance vs. Bias Voltage (DPY Package)](image1)

**Figure 8. Leakage Current vs. Temperature**

![Leakage Current vs. Temperature](image2)

**Figure 9. DC Voltage Sweep I-V Curve**

![DC Voltage Sweep I-V Curve](image3)

**Figure 10. Capacitance vs. Frequency**

![Capacitance vs. Frequency](image4)

**Figure 11. Insertion Loss**

![Insertion Loss](image5)
Figure 12. USB3.1 Gen 2 10-Gbps Eye Diagram (Bare Board)

Figure 13. USB3.1 Gen 2 10-Gbps Eye Diagram (with TPD1E0B04DPL)
7 Detailed Description

7.1 Overview
The TPD1E0B04 device is a bidirectional ESD Protection Diode with ultra-low capacitance. This device can dissipate ESD strikes at the maximum level specified by the IEC 61000-4-2 International Standard (contact). The ultra-low capacitance makes this device ideal for protecting any super high-speed signal pins including Thunderbolt 3. The low capacitance allows for extremely low losses even at RF frequencies such as USB 3.1 Gen 2, Thunderbolt 3, or antenna applications.

7.2 Functional Block Diagram

7.3 Feature Description

7.3.1 IEC 61000-4-2 ESD Protection
The I/O pins can withstand ESD events up to ±8-kV contact and ±9-kV air gap. An ESD-surge clamp diverts the current to ground.

7.3.2 IEC 61000-4-4 EFT Protection
The I/O pins can withstand an electrical fast transient burst of up to 80 A (5/50 ns waveform, 4 kV with 50-Ω impedance). An ESD-surge clamp diverts the current to ground.

7.3.3 IEC 61000-4-5 Surge Protection
The I/O pins can withstand surge events up to 1.7 A and 15 W (8/20 μs waveform). An ESD-surge clamp diverts this current to ground.

7.3.4 IO Capacitance
The capacitance between each I/O pin to ground is 0.13 pF (typical) and 0.15 pF (maximum). This device supports data rates in excess of 20 Gbps.

7.3.5 DC Breakdown Voltage
The DC breakdown voltage of each I/O pin is ±6.7 V (typical). This ensures that sensitive equipment is protected from surges above the reverse standoff voltage of ±3.6 V.

7.3.6 Ultra Low Leakage Current
The I/O pins feature an ultra-low leakage current of 10 nA (maximum) with a bias of ±2.5 V

7.3.7 Low ESD Clamping Voltage
The I/O pins feature an ESD clamp that is capable of clamping the voltage to 10.1 V (I_{pp} = 5 A).

7.3.8 Supports High Speed Interfaces
This device is capable of supporting high speed interfaces in excess of 20 Gbps, because of the extremely low IO capacitance.

7.3.9 Industrial Temperature Range
This device features an industrial operating range of −40°C to +125°C.
Feature Description (continued)

7.3.10 Industry Standard Package

The layout of this device makes it simple and easy to add protection to an existing layout. The package is offered in industry standard 0201 and 0402 footprints, requiring minimal modification to an existing layout.

7.4 Device Functional Modes

The TPD1E0B04 device is a passive integrated circuit that triggers when voltages are above $V_{BRF}$ or below $V_{BRR}$. During ESD events, voltages as high as ±9 kV (air) can be directed to ground via the internal diode network. When the voltages on the protected line fall below the trigger levels of TPD1E0B04 (usually within 10s of nanoseconds) the device reverts to passive.
8 Application and Implementation

NOTE
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI’s customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information
The TPD1E0B04 is a diode type TVS which is used to provide a path to ground for dissipating ESD events on high-speed signal lines between a human interface connector and a system. As the current from ESD passes through the TVS, only a small voltage drop is present across the diode. This is the voltage presented to the protected IC. The low \( R_{\text{DYN}} \) of the triggered TVS holds this voltage, \( V_{\text{CLAMP}} \), to a safe level for the protected IC.

8.2 Typical Applications

8.2.1 USB Type-C Application

Figure 14. USB Type-C for Thunderbolt 3 ESD Schematic
Typical Applications (continued)

8.2.1.1 Design Requirements

For this design example eight TPD1E0B04 devices and two TPD4E05U06 devices are being used in a USB Type-C for Thunderbolt 3 application. This provides a complete ESD protection scheme. Given the Thunderbolt 3 application, the parameters listed in Table 1 are known.

<table>
<thead>
<tr>
<th>DESIGN PARAMETER</th>
<th>VALUE</th>
</tr>
</thead>
<tbody>
<tr>
<td>Signal range on superspeed Lines</td>
<td>0 V to 3.6 V</td>
</tr>
<tr>
<td>Operating frequency on superspeed Lines</td>
<td>up to 10 GHz</td>
</tr>
<tr>
<td>Signal range on CC, SBU, and DP/DM Lines</td>
<td>0 V to 5 V</td>
</tr>
<tr>
<td>Operating frequency on CC, SBU, and DP/DM Lines</td>
<td>up to 480 MHz</td>
</tr>
</tbody>
</table>

8.2.1.2 Detailed Design Procedure

8.2.1.2.1 Signal Range

The TPD1E0B04 supports signal ranges between –3.6 V and 3.6 V, which supports the SuperSpeed pairs on the USB Type-C application. The TPD4E05U06 supports signal ranges between 0 V and 5.5 V, which supports the CC, SBU, and DP-DM lines.

8.2.1.2.2 Operating Frequency

The TPD1E0B04 has a 0.13 pF (typical) capacitance, which supports the Thunderbolt 3 data rates of 20 Gbps. The TPD4E05U06 has a 0.5-pF (typical) capacitance, which easily supports the CC, SBU, and DP-DM data rates.
8.2.1.3 Application Curves

Figure 15. USB 3.1 Gen 2 10-Gbps Eye Diagram (Bare Board)

Figure 16. USB 3.1 Gen 2 10-Gbps Eye Diagram (with TPD1E0B04DPL)

Figure 17. Insertion Loss
8.2.2 WiFi Antenna Application

![WiFi Antenna Schematic](image)

8.2.2.1 Design Requirements

For this design example one TPD1E0B04 device for a 5-GHz WiFi antenna application. This provides a complete ESD protection scheme.

Given the WiFi antenna application, the parameters listed in Table 2 are known.

<table>
<thead>
<tr>
<th>DESIGN PARAMETER</th>
<th>VALUE</th>
</tr>
</thead>
<tbody>
<tr>
<td>Signal range</td>
<td>–3.16 V to +3.16 V</td>
</tr>
<tr>
<td>Operating frequency</td>
<td>5.170 GHz to 5.835 GHz</td>
</tr>
</tbody>
</table>

8.2.2.2 Detailed Design Procedure

8.2.2.2.1 Signal Range

The TPD1E0B04 supports signal ranges between –3.6 V and 3.6 V, which supports the antenna signal range. The signal range shown assumes maximum transmit power of 200 mW into a 50-Ω antenna.

8.2.2.2.2 Operating Frequency

The TPD1E0B04 has a 0.13 pF (typical) capacitance, which supports extremely high data rates. The capacitance vs. frequency and bias voltages are exceedingly low, allowing for very low RF loss and known impedance characteristics. Since capacitance and loss changes very little across the operating frequencies, there must be minimal disturbance on the line.
8.2.2.3 Application Curves

Figure 19. Capacitance vs. Frequency

Figure 20. Capacitance vs. Bias Voltage

Figure 21. Insertion Loss
9 Power Supply Recommendations

This device is a passive ESD device so there is no need to power it. Take care not to violate the recommended I/O specification to ensure the device functions properly.

10 Layout

10.1 Layout Guidelines

- The optimum placement is as close to the connector as possible.
  - EMI during an ESD event can couple from the trace being struck to other nearby unprotected traces, resulting in early system failures.
  - The PCB designer must minimize the possibility of EMI coupling by keeping any unprotected traces away from the protected traces which are between the TVS and the connector.
- Route the protected traces as straight as possible.
- Eliminate any sharp corners on the protected traces between the TVS and the connector by using rounded corners with the largest radii possible.
  - Electric fields tend to build up on corners, increasing EMI coupling.

10.2 Layout Example

![Layout Diagram](image)

Figure 22. USB Type-C Mid-Mount, Hybrid Connector ESD Layout

Legend

- Top Layer
- Bottom Layer
- Pin to GND
- VIA to VBUS Plane
- VIA to other layer
- VIA to GND Plane
11 Device and Documentation Support

11.1 Documentation Support

11.1.1 Related Documentation
For related documentation see the following:
*TPD1E0B04 Evaluation Module User’s Guide, SLVUAN6*

11.2 Receiving Notification of Documentation Updates
To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.3 Community Resources
The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

**TI E2E™ Online Community** *TI's Engineer-to-Engineer (E2E) Community*. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.4 Trademarks
E2E is a trademark of Texas Instruments.
All other trademarks are the property of their respective owners.

11.5 Electrostatic Discharge Caution
This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.6 Glossary
*SLYZ022 — TI Glossary.*
This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information
The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.
## PACKAGING INFORMATION

<table>
<thead>
<tr>
<th>Orderable Device</th>
<th>Status (1)</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>Package Qty</th>
<th>Eco Plan (2)</th>
<th>Lead/Ball Finish</th>
<th>MSL Peak Temp (3)</th>
<th>Op Temp (°C)</th>
<th>Device Marking (4/5)</th>
<th>Samples</th>
</tr>
</thead>
<tbody>
<tr>
<td>TPD1E0B04DPLR</td>
<td>ACTIVE</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>15000</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>CU NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>8</td>
<td>Samples</td>
</tr>
<tr>
<td>TPD1E0B04DPLT</td>
<td>ACTIVE</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>250</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>CU NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>8</td>
<td>Samples</td>
</tr>
<tr>
<td>TPD1E0B04DPYR</td>
<td>ACTIVE</td>
<td>X1SON</td>
<td>DPY</td>
<td>2</td>
<td>10000</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>CU NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>5D</td>
<td>Samples</td>
</tr>
<tr>
<td>TPD1E0B04DPYT</td>
<td>ACTIVE</td>
<td>X1SON</td>
<td>DPY</td>
<td>2</td>
<td>250</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>CU NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 125</td>
<td>5D</td>
<td>Samples</td>
</tr>
</tbody>
</table>

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.
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**TAPE AND REEL INFORMATION**

<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Reel Diameter (mm)</th>
<th>Reel Width W1 (mm)</th>
<th>A0 (mm)</th>
<th>B0 (mm)</th>
<th>K0 (mm)</th>
<th>P1 (mm)</th>
<th>W (mm)</th>
<th>Pin1 Quadrant</th>
</tr>
</thead>
<tbody>
<tr>
<td>TPD1E0B04DPLR</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>15000</td>
<td>178.0</td>
<td>12.3</td>
<td>0.39</td>
<td>0.68</td>
<td>0.38</td>
<td>2.0</td>
<td>8.0</td>
<td>Q1</td>
</tr>
<tr>
<td>TPD1E0B04DPLR</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>15000</td>
<td>178.0</td>
<td>8.4</td>
<td>0.36</td>
<td>0.66</td>
<td>0.33</td>
<td>2.0</td>
<td>8.0</td>
<td>Q1</td>
</tr>
<tr>
<td>TPD1E0B04DPLT</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>250</td>
<td>178.0</td>
<td>8.4</td>
<td>0.36</td>
<td>0.66</td>
<td>0.33</td>
<td>2.0</td>
<td>8.0</td>
<td>Q1</td>
</tr>
<tr>
<td>TPD1E0B04DPYR</td>
<td>X1SON</td>
<td>DPY</td>
<td>2</td>
<td>10000</td>
<td>180.0</td>
<td>9.5</td>
<td>0.66</td>
<td>1.15</td>
<td>0.66</td>
<td>2.0</td>
<td>8.0</td>
<td>Q1</td>
</tr>
<tr>
<td>TPD1E0B04DPYT</td>
<td>X1SON</td>
<td>DPY</td>
<td>2</td>
<td>250</td>
<td>180.0</td>
<td>9.5</td>
<td>0.66</td>
<td>1.15</td>
<td>0.66</td>
<td>2.0</td>
<td>8.0</td>
<td>Q1</td>
</tr>
</tbody>
</table>

*All dimensions are nominal.*

**TAPE DIMENSIONS**

- **A0**: Dimension designed to accommodate the component width
- **B0**: Dimension designed to accommodate the component length
- **K0**: Dimension designed to accommodate the component thickness
- **W**: Overall width of the carrier tape
- **P1**: Pitch between successive cavity centers

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This page is from the package materials page of a document, containing information on tape and reel dimensions for different devices. The table lists various devices with their corresponding package type, drawing, pins, Reel Diameter, Reel Width, and dimensions for specific parts of the reel or components. The diagram illustrates the reel dimensions and quadrant assignments for pin orientation in tape. All dimensions are nominal, indicating they are approximate values used for manufacturing and handling purposes. The page is part of a larger set of materials provided by Texas Instruments, with a specific date of 5-Jul-2017 noted at the bottom.
### TAPE AND REEL BOX DIMENSIONS

*All dimensions are nominal*

<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Length (mm)</th>
<th>Width (mm)</th>
<th>Height (mm)</th>
</tr>
</thead>
<tbody>
<tr>
<td>TPD1E0B04DPLR</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>15000</td>
<td>184.0</td>
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<td>19.0</td>
</tr>
<tr>
<td>TPD1E0B04DPLR</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>15000</td>
<td>205.0</td>
<td>200.0</td>
<td>33.0</td>
</tr>
<tr>
<td>TPD1E0B04DPLT</td>
<td>X2SON</td>
<td>DPL</td>
<td>2</td>
<td>250</td>
<td>205.0</td>
<td>200.0</td>
<td>33.0</td>
</tr>
<tr>
<td>TPD1E0B04DPYR</td>
<td>X1SON</td>
<td>DPY</td>
<td>2</td>
<td>10000</td>
<td>184.0</td>
<td>184.0</td>
<td>19.0</td>
</tr>
<tr>
<td>TPD1E0B04DPYT</td>
<td>X1SON</td>
<td>DPY</td>
<td>2</td>
<td>250</td>
<td>184.0</td>
<td>184.0</td>
<td>19.0</td>
</tr>
</tbody>
</table>
NOTE:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Small Outline No–Lead (SON) package configuration.
D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
NOTES:  
A. All linear dimensions are in millimeters. 
B. This drawing is subject to change without notice. 
C. Publication IPC-7351 is recommended for alternate designs. 
D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads. 
E. Maximum stencil thickness 0.127 mm (5 mils). All linear dimensions are in millimeters. 
F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations. 
G. Side aperture dimensions over-print land for acceptable area ratio > 0.66. Customer may reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.
MECHANICAL DATA

DPY (R-PX1SON-N2)  PLASTIC SMALL OUTLINE NO-LEAD

1.10
0.90
A

0.70
0.50
B

0.45
0.30
C

0.08
0.05
0.00

0.70
0.60

0.55
0.45

0.30
0.20

0.05

NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5-1994.
B. This drawing is subject to change without notice.
C. SON (Small Outline No-Lead) package configuration.
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